Attorney's Docket No. 5470.285DV PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re: DeSimone et al.
Serial No.: To be assigned
Filed: Concurrently herewith
For: METHODS OF FORMING POLYMERIC STRUCTURES USING CARBON DIOXIDE AND POLYMERIC STRUCTURES FORMED THEREBY

Date: February 23, 2004

Mail Stop Patent Application
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT
CITATION UNDER 37 C.F.R. § 1.97

Sir:

Attached is a list of documents on forms PTO-1449.. All items listed on the PTO-1449s were cited in parent application Serial No. 10/109,588, filed March 28, 2002. Since the benefit of this application is claimed under 35 U.S.C. §120, no other copies need to be furnished in accordance with 37 C.F.R. §1.98(d); however, copies will be furnished on request. It is requested that these documents be considered by the Examiner and officially made of record in accordance with the provisions of 37 C.F.R. §1.97 and Section 609 of the MPEP.

Respectfully submitted,

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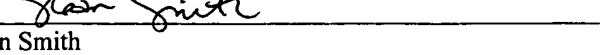

Sloan Smith

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Sheet 1 of

U.S. PATENT AND TRADEMARK OFFICE — AUG 09 2002

Complete if Known	
Application Number	~~10/109,588~~ To Be Assigned
Filing Date	~~March 28, 2002~~ Concurrently herewith
First Named Inventor	Joseph M. DeSimone
Group Art Unit	~~1772~~
Examiner Name	Unknown
Attorney Docket Number	5470.351DV

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No.	U.S. Patent Document Number	Kind Code (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T
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Examiner Signature		Date Considered	5/03

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449 U.S. Department of Commerce Patent and Trademark Office LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)	Attorney Docket Number 5470-351DV	Serial No. ~~10/109,588~~ To Be Assigned
	Applicants: Joseph M. DeSimone et al;	
	Filing Date: ~~March 28, 2002~~ Concurrently herewith	Group ~~1711~~

U. S. PATENTS & PATENT APPLICATION PUBLICATIONS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate

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		Document Number	Date	Country	Class	Subclass	Translation Yes | No
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	3.	J.L. Hedrick et al; "Templating Nanoporosity in Thin-Film Dielectric Insulators"; Adv. Mater. 10, No. 13 pp 1049-1053, 1998.
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EXAMINER Mostafa Fahmi DATE CONSIDERED 11/03

*EXAMINER Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.